The European Dependable Computing Conference (EDCC) is a pivotal event in the domain of dependable and secure computing systems. It serves as a unique forum for researchers and practitioners to present and discuss their latest research results on theory, techniques, systems, and tools for the design, validation, operation and evaluation of dependable and secure computing systems.

In addition to original research papers, EDCC welcomes contributions on dependability and security in practice and their application to industrial domains. The conference also provides a natural meeting place for ongoing dependability and security projects to present their state of advancement and innovative results.

The conference covers a broad perspective on dependability and security, which includes, but is not limited to:

- Hardware and software architecture of dependable systems;
- Dependability and security modelling, evaluation, benchmarking, and tools;
- Safety-critical systems design and analysis;
- Artificial Intelligence for dependability and security;
- Fault-tolerant networks, protocols and systems;
- Time-sensitive networks and ultra-reliable low-latency communication;
- Mixed-criticality systems design and evaluation;
- Testing and validation methods;
- Dependability and security of:
  - Artificial Intelligence systems;
  - Cyber-physical systems, e.g. smart grids, intelligent vehicles, (Industrial) Internet of Things;
  - Cloud, fog, and edge computing systems;
  - Data analytics application;
  - Databases and distributed ledgers (including blockchains);
- Data protection and data privacy;

The conference invites submissions in the following categories: regular papers (up to 8 pages), practical experience reports (up to 6 pages), industry papers (from 4 up to 6 pages), and short papers (up to 4 pages).

The conference program will be enriched by workshops, a student forum, fast abstracts and posters tracks, offering an ideal venue for exchanging ideas and networking.

The conference proceedings will be published by IEEE Conference Publishing Services (CPS) and will be submitted to IEEE Xplore.